

**FEATURES**

- Single Active Area
- Detection to 1 nm
- Stable Response after Exposure to EUV/UV Conditions
- Protective Cover Plate<sup>2</sup>

**Electro-Optical Characteristics at 25 °C**

Parameters	Test Conditions	Min	Typ	Max	Units
Active Area	10 mm x 10 mm		100		mm <sup>2</sup>
Responsivity	(see graph on next page)				A/W
Shunt Resistance, Rsh	@ ± 10 mV	10			MOhms
Reverse Breakdown Voltage, V <sub>R</sub>	I <sub>R</sub> = μA	10			Volts
Capacitance, C	V <sub>R</sub> = 0 V		5	15	nF
Response Time, tr	RL = 50 Ω, V <sub>R</sub> = 8 V			6	μ sec

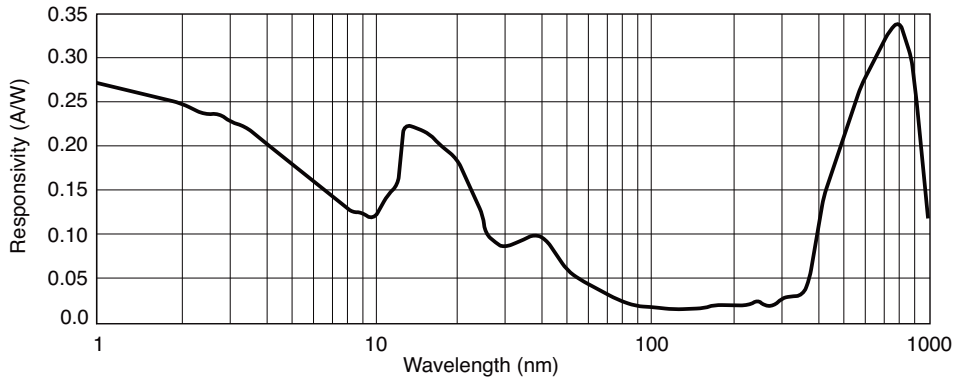
**Thermal Parameters**

Storage and Operating Temperature Range	Units
Ambient	-10 ° to 40 °C
Nitrogen or Vacuum	-20 °C to 80 °C
Lead Soldering Temperature <sup>1</sup>	260 °C

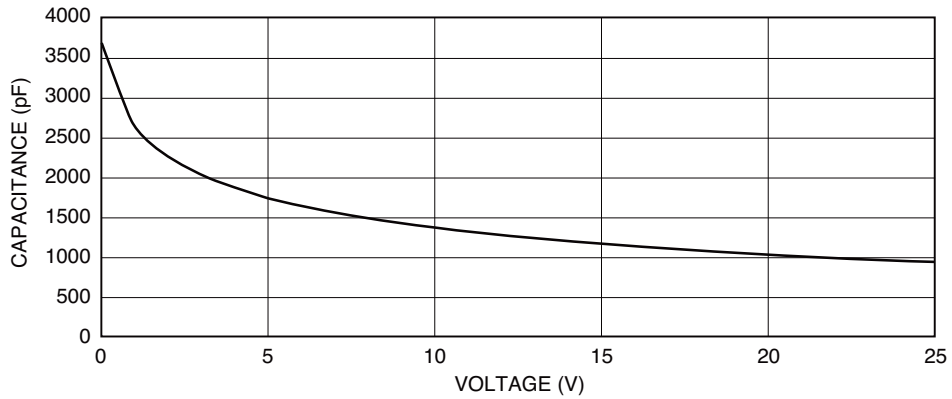
<sup>1</sup> 0.080" from case for 10 seconds.

<sup>2</sup> Shipped with temporary cover to protect the photodiode and wire bonds.  
 Review the Application Note, "Handling Precautions for AXUV, SXUV, and UVG Detectors", prior to removing cover.

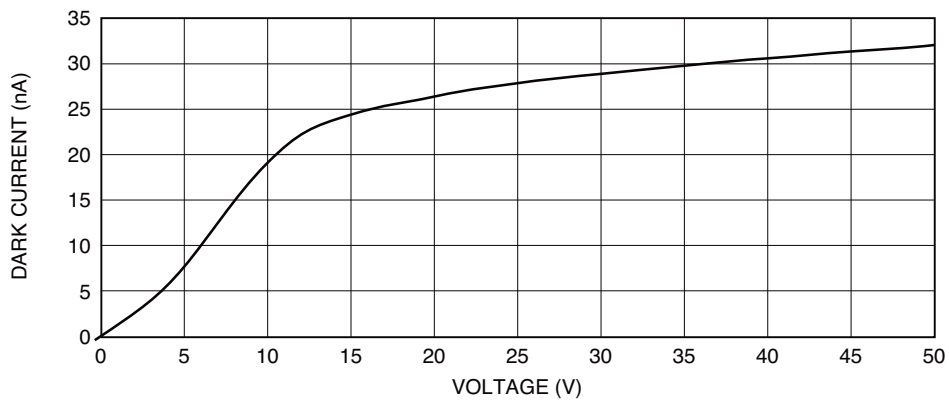
Typical Photon Responsivity



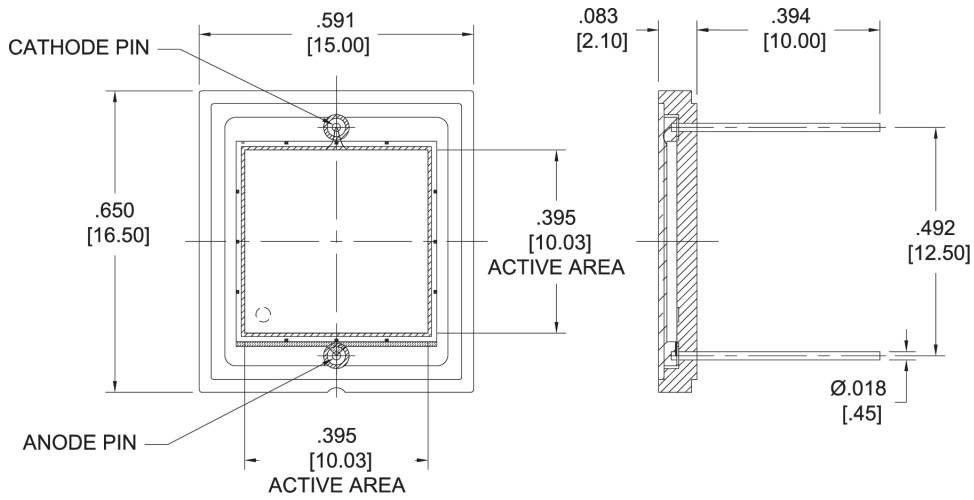
Capacitance vs. Voltage



Dark Current vs. Voltage



**Package Information**



Dimensions are in inch [metric] units.

Specifications are subject to change without prior notice.